## Notice of References Cited Application/Control No. 10/634,047 Examiner Mark L. Berch Applicant(s)/Patent Under Reexamination MAIER ET AL. Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2006/0094722	05-2006	Yasuda et al.	514/248
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